

### SEMITRANS<sup>®</sup> 2

#### SKM150GAR12V

#### Features

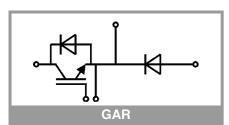
- V-IGBT = 6. Generation Trench V-IGBT (Fuji)
- CAL4 = Soft switching 4. Generation CAL-diode
- Insulated copper baseplate using DBC technology (Direct Copper Bonding)
- Increased power cycling capability
- With integrated gate resistor
- UL recognized, file no. E63532
- Lowest switching losses at High di/dt

#### **Typical Applications\***

- Electronic welders
- DC/DC converter
- Brake chopper
- Switched reluctance motor

#### Remarks

- Case temperature limited to T<sub>c</sub> = 125°C max.
- Recommended  $T_{op} = -40 \dots +150^{\circ}C$
- Product reliability results valid for T<sub>j</sub> = 150°C



Absolute	Maximum Ratin	gs		
Symbol	Conditions		Values	Unit
IGBT				
V <sub>CES</sub>	T <sub>j</sub> = 25 °C		1200	V
lc	T <sub>i</sub> = 175 °C	T <sub>c</sub> = 25 °C	231	А
	$1_j = 1/5^{-1}$ C	T <sub>c</sub> = 80 °C	176	Α
I <sub>Cnom</sub>			150	A
I <sub>CRM</sub>	$I_{CRM} = 3 \times I_{Cnom}$		450	Α
V <sub>GES</sub>			-20 20	V
t <sub>psc</sub>	$V_{CC} = 720 V$ $V_{GE} \le 15 V$ $V_{CES} \le 1200 V$	T <sub>j</sub> = 125 °C	10	μs
Tj			-40 175	°C
Inverse d	iode			
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	189	Α
·		T <sub>c</sub> = 80 °C	141	Α
I <sub>Fnom</sub>	_		150	Α
I <sub>FRM</sub>	I <sub>FRM</sub> = 3xI <sub>Fnom</sub>		450	A
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms, sin 180°, T <sub>i</sub> = 25 °C		900	Α
Tj			-40 175	°C
Freewhee	ling diode			
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	189	Α
		T <sub>c</sub> = 80 °C	141	A
I <sub>Fnom</sub>	_		150	Α
I <sub>FRM</sub>	I <sub>FRM</sub> = 3xI <sub>Fnom</sub>		450	Α
I <sub>FSM</sub>	$t_p = 10 \text{ ms, sin } 180^\circ, T_j = 25 \text{ °C}$		900	Α
Tj			-40 175	°C
Module	•	I		
I <sub>t(RMS)</sub>			200	А
T <sub>stq</sub>			-40 125	°C
Visol	AC sinus 50 Hz, t = 1 min		4000	V

Characte	eristics					
Symbol	Conditions	min.	typ.	max.	Unit	
IGBT						•
V <sub>CE(sat)</sub>	I <sub>C</sub> = 150 A	T <sub>j</sub> = 25 °C		1.75	2.20	V
	V <sub>GE</sub> = 15 V chiplevel	T <sub>j</sub> = 150 °C		2.20	2.48	V
V <sub>CE0</sub>	chiplevel	T <sub>j</sub> = 25 °C		0.94	1.04	V
		T <sub>j</sub> = 150 °C		0.88	0.98	V
r <sub>CE</sub>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25 °C		5.4	7.7	mΩ
	chiplevel	T <sub>j</sub> = 150 °C		8.8	10	mΩ
V <sub>GE(th)</sub>	$V_{GE}=V_{CE}, I_C = 6 \text{ mA}$		5.5	6	6.5	V
I <sub>CES</sub>	V <sub>GE</sub> = 0 V V <sub>CE</sub> = 1200 V	T <sub>j</sub> = 25 °C			0.3	mA
		T <sub>j</sub> = 150 °C		-		mA
Cies	V <sub>CE</sub> = 25 V V <sub>GE</sub> = 0 V	f = 1 MHz		9.0		nF
C <sub>oes</sub>		f = 1 MHz		0.89		nF
C <sub>res</sub>		f = 1 MHz		0.88		nF
Q <sub>G</sub>	V <sub>GE</sub> = - 8 V+ 15 V			1650		nC
R <sub>Gint</sub>	T <sub>j</sub> = 25 °C			5.0		Ω



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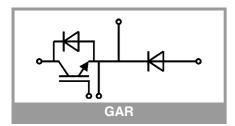
#### **Typical Applications\***

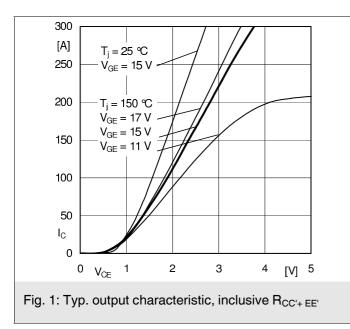
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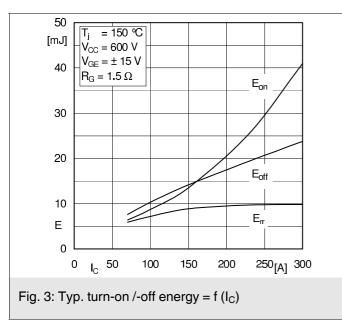
#### Remarks

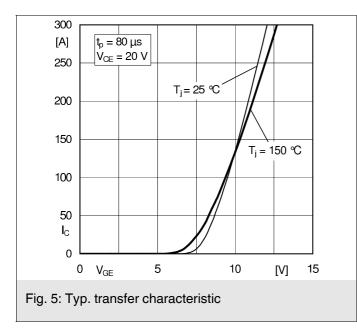
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- Recommended  $T_{op} = -40 \dots +150^{\circ}C$
- Product reliability results valid for  $T_j = 150^{\circ}C$

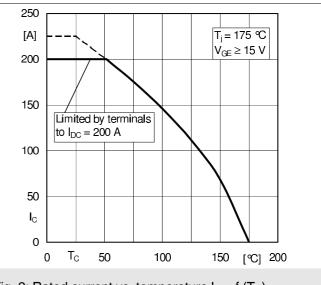
Characte	ristics					
Symbol	Conditions		min.	typ.	max.	Unit
t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V	T <sub>j</sub> = 150 °C		258		ns
t <sub>r</sub>	$I_{\rm C} = 150 \rm{A}$	T <sub>j</sub> = 150 °C		32		ns
Eon	$V_{GE} = +15/-15 V$ R <sub>G on</sub> = 1.5 Ω	T <sub>j</sub> = 150 °C		13.5		mJ
t <sub>d(off)</sub>	$R_{G off} = 1.5 \Omega$	T <sub>j</sub> = 150 °C		388		ns
t <sub>f</sub>	di/dt <sub>on</sub> = 5400 A/µs	T <sub>j</sub> = 150 °C		62		ns
E <sub>off</sub>	di/dt <sub>off</sub> = 1800 A/µs du/dt = 8100 V/µs	T <sub>j</sub> = 150 °C		14.2		mJ
R <sub>th(j-c)</sub>	per IGBT				0.19	K/W
Inverse d	iode					
$V_F = V_{EC}$	I <sub>F</sub> = 150 A	T <sub>j</sub> = 25 °C		2.14	2.46	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.07	2.38	V
V <sub>F0</sub>		T <sub>i</sub> = 25 °C		1.30	1.50	V
	chiplevel	T <sub>i</sub> = 150 °C		0.90	1.10	V
r <sub>F</sub>		T <sub>i</sub> = 25 °C		5.6	6.4	mΩ
-	chiplevel	T <sub>i</sub> = 150 °C		7.8	8.5	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 150 A	T <sub>i</sub> = 150 °C		165		Α
Q <sub>rr</sub>	$di/dt_{off} = 5800 \text{ A/}\mu\text{s}$	T <sub>i</sub> = 150 °C		22		μC
Err	V <sub>GE</sub> = ±15 V V <sub>CC</sub> = 600 V	T <sub>j</sub> = 150 °C		8.5		mJ
R <sub>th(j-c)</sub>	per diode				0.31	K/W
	ling diode					
$V_F = V_{EC}$	I <sub>F</sub> = 150 A	T <sub>j</sub> = 25 °C		2.14	2.46	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.07	2.38	V
V <sub>F0</sub>	- chiplevel	T <sub>i</sub> = 25 °C		1.30	1.50	V
		T <sub>i</sub> = 150 °C		0.90	1.10	V
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E <sub>rr</sub>	V <sub>GE</sub> = ±15 V V <sub>CC</sub> = 600 V	T <sub>i</sub> = 150 °C		8.5		mJ
R <sub>th(j-c)</sub>	per diode	J			0.31	K/W
Module	1		1			
L <sub>CE</sub>				30		nH
R <sub>CC'+EE'</sub>	measured per	T <sub>C</sub> = 25 °C		0.65		mΩ
• 400 +EE	switch	$T_{\rm C} = 125 ^{\circ}{\rm C}$		1.09		mΩ
R <sub>th(c-s)</sub>	calculated without thermal coupling			0.04	0.05	K/W
M <sub>s</sub>	$(\lambda_{grease}=0.81 \text{ W/(m*K)})$ to heat sink M6		3		5	Nm
M <sub>t</sub>		to terminals M5	2.5		5	Nm
WIt	-1		2.5		5	Nm
\M/					160	
W					100	g

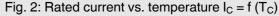


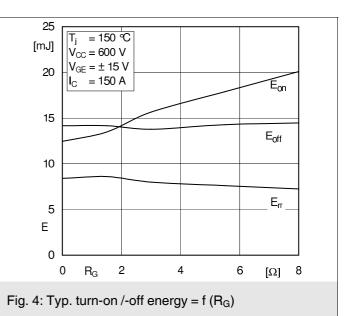


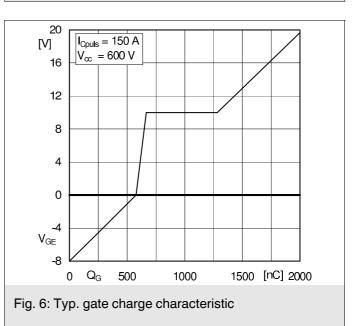




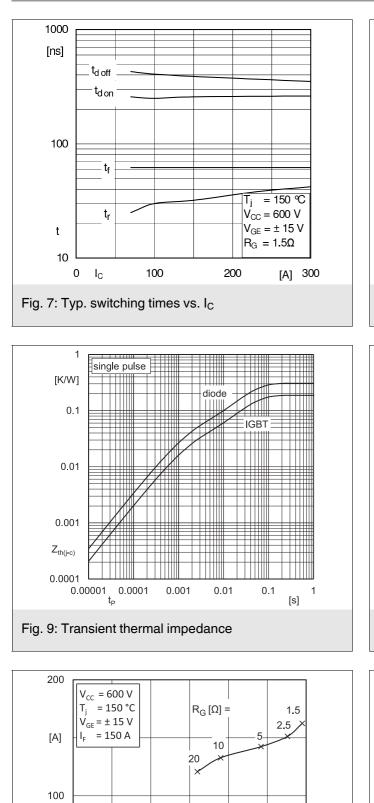


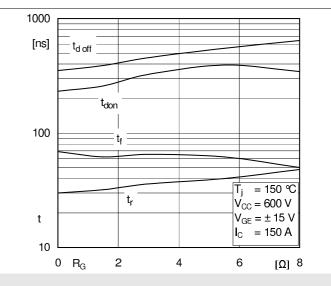


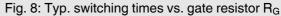


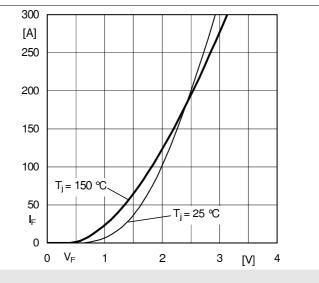


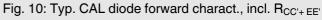
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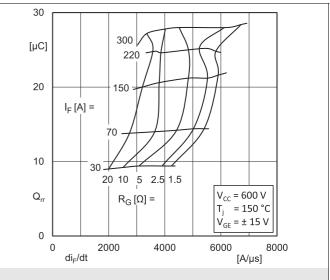


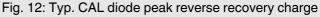












 $I_{RR}$ 

0

0

di<sub>F</sub>/dt

2000

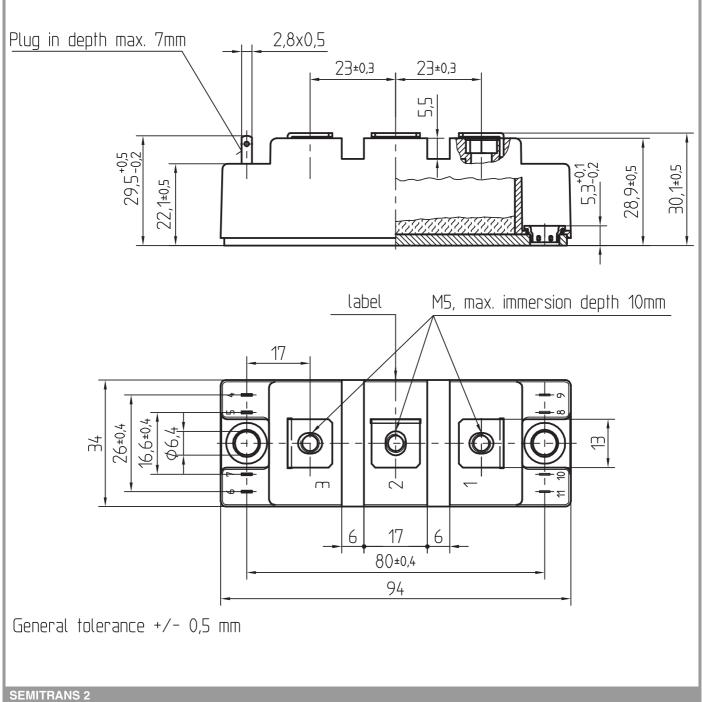
Fig. 11: CAL diode peak reverse recovery current

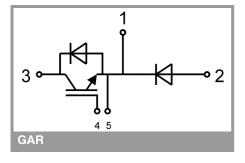
4000

[A/µs]

6000

Dimensions in mm





Rev. 1.0 - 31.01.2019

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

#### **\*IMPORTANT INFORMATION AND WARNINGS**

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